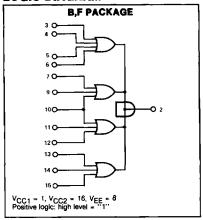
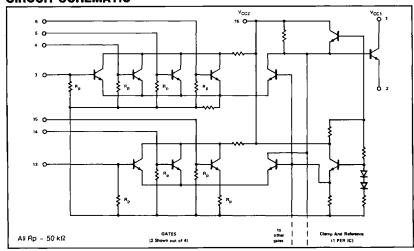
## **LOGIC DIAGRAM**



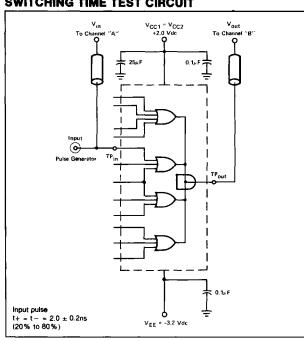
# **FEATURES**

- · Fast propagation delay for 2 logic levels = 2.3 ns TYP
- · Low power dissipation = 100 mW/package TYP (no load)
- · High fanout capability can drive  $50\Omega$
- High Z inputs internal 50 k $\Omega$  pulldowns
- · High immunity from power supply variations:  $V_{EE} = -5.2V \pm 5\%$ recommended
- Open emitter logic and bussing capability

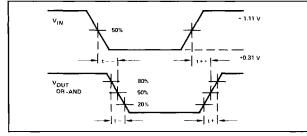
### CIRCUIT SCHEMATIC



### **SWITCHING TIME TEST CIRCUIT**



# PROPAGATION DELAY WAVEFORMS @ 25°C



- 1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 2 mV with an air flow of 200 linear fpm.
- Outputs are terminated through a 50-ohm resistor to 2.0 volts.

  2. For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be <% inch from TP<sub>n</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are con-
- nected to a 50-ohm resistor to ground.

  3. Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.